



Schweizerische Eidgenossenschaft

Confédération suisse

Confederazione Svizzera

Confederaziun svizra

Swiss Confederation

Federal Department of Economic Affairs,
Education and Research EAER

State Secretariat for Economic Affairs SECO

Swiss Accreditation Service SAS

SCS Directory

Accreditation number: SCS 0006

International standard: ISO/IEC 17025:2017

Swiss standard: SN EN ISO/IEC 17025:2018

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Initial accreditation: 10.07.1987
Current accreditation: 15.12.2023 to 14.12.2028
Scope of accreditation see: www.sas.admin.ch
(Accredited bodies)

Scope of accreditation as of 15.12.2023

Calibration laboratory for length and angles

Calibration and Measurement Capability (CMC)

Measured Quantity / Instrument or Gauge	Measurement Range	Measurement Conditions	Best Measurement Capability \pm ¹⁾	Remarks
LENGTH Machine tools	up to 40 m		$0,5 \mu\text{m} + 3 \cdot 10^{-6} \cdot L$	Positioning precision with laser interferometer On-site calibration
Length measuring instruments Horizontal instruments	up to 3 m		$0,2 \mu\text{m} + 2 \cdot 10^{-6} \cdot L$	Error of indication, with laser interferometer and gauge blocks
Height gauges	up to 1 m up to 3 m		$0,2 \mu\text{m} + 2 \cdot 10^{-6} \cdot L$	With step gauge With laser interferometer Also on-site calibration



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Measured Quantity / Instrument or Gauge	Measurement Range	Measurement Conditions	Best Measurement Capability \pm ¹⁾	Remarks
Electronic length indicator	up to 12 mm		$0,3 \mu\text{m} + 2,5 \cdot 10^{-6} \cdot L$	Comparison with reference length indicator
Setting gauge for probe constant	5 mm – 50 mm		0,4 μm 0,5 μm	Using coordinate measuring machine; Measurement uncertainty according to ISO 15530-3 On-site calibration
Distance gauge sphere to plane				Using coordinate measuring machine;
Distance	0 mm – 100 mm		0,6 μm	Measurement uncertainty according to ISO 15530-3
Diameter	up to 50 mm		0,6 μm	
Roundness			0,5 μm	
Hole plate				Using coordinate measuring machine;
Distance	up to 700 mm x 600 mm		$1,0 \mu\text{m} + 1,5 \cdot 10^{-6} \cdot L$	Measurement uncertainty according to ISO 15530-3
Diameter	up to 50 mm		0,8 μm	
Coordinate measuring machines	up to 1 m		Uncertainty of the standards used: Uncertainty of the standards used: Gauge blocks: $0,05 \mu\text{m} + 0,5 \cdot 10^{-6} \cdot L$ Reference sphere: $0,08 \mu\text{m}$	Acceptance test using calibration artefacts according to ISO 10360-2 Also on-site calibration
Measuring microscopes and projectors	up to 200 mm x 300 mm			Calibration with photo mask
2-D position deviation	Interval of division 10 mm		$1,2 \mu\text{m} + 5 \cdot 10^{-6} \cdot L$	Also on-site calibration
Gauge blocks	up to 3000 mm		$0,3 \mu\text{m} + 1,6 \cdot 10^{-6} \cdot L$	Length measuring machine with laser interferometer and mechanical probing
Step gauges	up to 1200 mm		$0,3 \mu\text{m} + 1,6 \cdot 10^{-6} \cdot L$	
Ball Bars	100 mm – 3000 mm		$0,6 \mu\text{m} + 0,5 \cdot 10^{-6} \cdot L$	



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Measured Quantity / Instrument or Gauge	Measurement Range	Measurement Conditions	Best Measurement Capability \pm ¹⁾	Remarks
Line scales	Engineer scale up to 3000 mm		3 μm + 2•10 ⁻⁶ •L	Length measuring machine with laser interferometer and optical probing
	Standard scale up to 3000 mm		5 μm + 0.8•10 ⁻⁶ •L	
	Glass scale up to 1000 mm		0,5 μm + 0,5•10 ⁻⁶ •L	
Guideways	$L \leq 3 \text{ m}$		0,1 μm + 0,4•10 ⁻⁶ •L + 0,025•A	on-site calibration
				With straightness interferometer
				L = measured length A = indicated value
Straightness standards	$L \leq 15 \text{ m}$		0,2 μm + (0,15+ $B/2000$) •10 ⁻⁶ •L	With angle interferometer or electronic levels B = base length in mm
Straight edges	up to 3 m			STRAIGHT-line method
Straightness			0,15 μm + 0,15•10 ⁻⁶ •L+ 0,02•A	L = measured length A = indicated value
Parallelism			0,2 μm + 0,25•10 ⁻⁶ •L+ 0,02•A	
Squareness standards	up to 1400 mm		0,5 μm + 0,5•10 ⁻⁶ •L+ 0,02•A	STRAIGHT-line method (specimen reclining)
	up to 1000 mm		0,2 μm + 0,2•10 ⁻⁶ •L+ 0,02•A	SQUARE-master method (specimen upright)
	up to 500 mm		0,2 μm + 1,5•10 ⁻⁶ •L + 0,02•A	With rotatory table and STRAIGHT-line L = length A = indicated value



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Measured Quantity / Instrument or Gauge	Measurement Range	Measurement Conditions	Best Measurement Capability \pm ¹⁾	Remarks
Surface plates				
Flatness	Minimal size 0,2 m x 0,2 m		$0,5 \mu\text{m} + 0,5 \cdot 10^{-6} \cdot L$	Electronic levels L = length Also on-site calibration
Flatness artifacts				
Flatness and parallelism	Surface $> 1 \text{ cm}^2$ up to 3000 mm		$0,4 \mu\text{m} + 0,5 \cdot 10^{-6} \cdot L$	TOPO-method L = measured length
ANGLE				
Angular deviation of guideways	up to 100"		$0,2'' + 2 \cdot 10^{-3} \cdot A + 0,05'' \cdot L$	Angle interferometer A = value L = measured length in m Also on-site calibration
Dividing heads	Full circle		1.2"	
Rotary tables / Position error of rotary axes	1° or arbitrary interval		1.2"	With rotary axis calibrator, or index table with angle interferometer or electronic level
	10° interval		0,5"	Optical polygon and autocollimator Also on-site calibration
Inclinometers	360° 1° interval		2,5"	With index table
Electronic levels / Bubble levels	$\pm 1^\circ$ arbitrary interval		$0,2'' + 2 \cdot 10^{-3} \cdot A$	With inclination table and angle interferometer
Angle encoders	360° arbitrary interval		10"	With rotary table
Optical polygons	360° arbitrary interval		0,3"	With rotary table and autocollimator

In case of contradictions in the language versions of the directories, the German version shall apply.

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